

Notice of References Cited

Application/Control No.	Reexamination	Applicant(s)/Patent Under Reexamination SEKIGUCHI ET AL.		
Examiner	Art Unit			
Neveen Abel-Jalil	2175	Page 1 of 1		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2004/0073831	04-2004	Yanai et al.	714/007
	В	US-			
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
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	ı	US-			
	J	US-			
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FOREIGN PATENT DOCUMENTS

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	N					
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	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	Yanai et al. Continuation of application No. 09/709,814, filed on Nov. 10, 2000, now Pat. No. 6,502,205.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.